



## Atomic Force Microscope



**NT-MDT NTEGRA AFM microscope**

Our laboratory is equipped with an NT-MDT NTEGRA AFM microscope. We use this microscope to characterize the roughness of our samples, on a typical lateral scale of microns. The vertical resolution of the instrument is under the nanometer scale. The instrument works in ambient conditions. Both contact and non-contact mode scanning can be performed. Topographic and phase images can be simultaneously acquired. Optionally, magnetic tips can be used to study magnetic properties at room temperature.